Welcome to [E-XFL.COM](#)**What is "Embedded - Microcontrollers"?**

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"**Details**

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	34
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 12x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	PG-VQFN-48-73
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1403q048x0128aaxuma1

Edition 2016-10

Published by

**Infineon Technologies AG
81726 Munich, Germany**

**© 2016 Infineon Technologies AG
All Rights Reserved.**

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.

Table of Contents

Table of Contents

1	Summary of Features	9
1.1	Device Overview	11
1.2	Ordering Information	12
1.3	Device Types	13
1.4	Chip Identification Number	15
2	General Device Information	18
2.1	Logic Symbols	18
2.2	Pin Configuration and Definition	22
2.2.1	Package Pin Summary	26
2.2.2	Port Pin for Boot Modes	30
2.2.3	Port I/O Function Description	31
2.2.4	Hardware Controlled I/O Function Description	32
3	Electrical Parameter	41
3.1	General Parameters	41
3.1.1	Parameter Interpretation	41
3.1.2	Absolute Maximum Ratings	42
3.1.3	Pin Reliability in Overload	43
3.1.4	Operating Conditions	45
3.2	DC Parameters	46
3.2.1	Input/Output Characteristics	46
3.2.2	Analog to Digital Converters (ADC)	50
3.2.3	Out of Range Comparator (ORC) Characteristics	54
3.2.4	Analog Comparator Characteristics	56
3.2.5	Temperature Sensor Characteristics	57
3.2.6	Oscillator Pins	58
3.2.7	Power Supply Current	62
3.2.8	Flash Memory Parameters	68
3.3	AC Parameters	70
3.3.1	Testing Waveforms	70
3.3.2	Power-Up and Supply Threshold Characteristics	71
3.3.3	On-Chip Oscillator Characteristics	73
3.3.4	Serial Wire Debug Port (SW-DP) Timing	74
3.3.5	SPD Timing Requirements	75
3.3.6	Peripheral Timings	76
3.3.6.1	Synchronous Serial Interface (USIC SSC) Timing	76
3.3.6.2	Inter-IC (IIC) Interface Timing	79
3.3.6.3	Inter-IC Sound (IIS) Interface Timing	81
4	Package and Reliability	83
4.1	Package Parameters	83

Summary of Features

1 Summary of Features

The XMC1400 devices are members of the XMC1000 Family of microcontrollers based on the ARM Cortex-M0 processor core. The XMC1400 series addresses the real-time control needs of motor control and digital power conversion. It also features peripherals for LED Lighting applications and Human-Machine Interface (HMI).

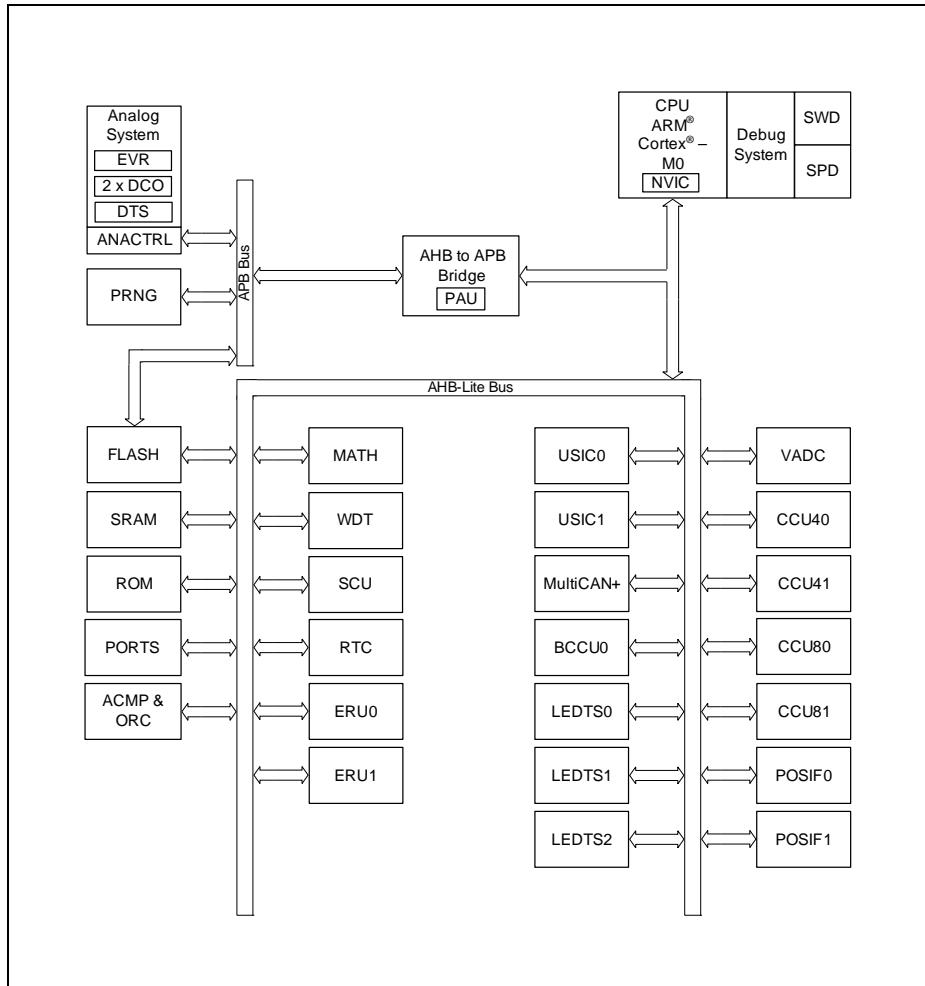


Figure 1 Block Diagram

General Device Information

2.2 Pin Configuration and Definition

The following figures summarize all pins, showing their locations on the different packages.

Top View		
P2.4	1	38
P2.5	2	37
P2.6	3	36
P2.7	4	35
P2.8	5	34
P2.9	6	33
P2.10	7	32
P2.11	8	31
V _{SSP} /V _{SS}	9	30
V _{DDP} /V _{DD}	10	29
P1.5	11	28
P1.4	12	27
P1.3	13	26
P1.2	14	25
P1.1	15	24
P1.0	16	23
P0.0	17	22
P0.1	18	21
P0.2	19	20

Figure 6 XMC1400 PG-TSSOP-38-9 Pin Configuration (top view)

General Device Information

2.2.1 Package Pin Summary

The following general building block is used to describe each pin:

Table 4 Package Pin Mapping Description

Function	Package A	Package B	...	Pad Type
Px.y	N	N		Pad Class

The table is sorted by the “Function” column, starting with the regular Port pins (Px.y), followed by the supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The “Pad Type” indicates the employed pad type:

- STD_INOUT (standard bi-directional pads)
- STD_INOUT/AN (standard bi-directional pads with analog input)
- STD_INOUT/clock (standard bi-directional pads with oscillator function)
- High Current (high current bi-directional pads)
- STD_IN/AN (standard input pads with analog input)
- Power (power supply)

Details about the pad properties are defined in the Electrical Parameter chapter.

Table 5 Package Pin Mapping

Function	LQFP 64, VQFN 64	VQFN 48	VQFN 40	TSSOP 38	Pad Type	Notes
P0.0	41	29	23	17	STD_INOUT	
P0.1	42	30	24	18	STD_INOUT	
P0.2	43	31	25	19	STD_INOUT	
P0.3	44	32	26	20	STD_INOUT	
P0.4	45	33	27	21	STD_INOUT	
P0.5	46	34	28	22	STD_INOUT	
P0.6	47	35	29	23	STD_INOUT	
P0.7	48	36	30	24	STD_INOUT	
P0.8/ RTC_ XTAL1	51	39	33	27	STD_INOUT /clock_IN	

General Device Information
Table 5 Package Pin Mapping (cont'd)

Function	LQFP 64, VQFN 64	VQFN 48	VQFN 40	TSSOP 38	Pad Type	Notes
P2.8	17	11	9	5	STD_IN/AN	
P2.9	18	12	10	6	STD_IN/AN	
P2.10	19	13	11	7	STD_INOUT /AN	
P2.11	20	14	12	8	STD_INOUT /AN	
P2.12	21	15	-	-	STD_INOUT /AN	
P2.13	22	16	-	-	STD_INOUT /AN	
P3.0	36	28	-	-	STD_INOUT	
P3.1	37	-	-	-	STD_INOUT	
P3.2	38	-	-	-	STD_INOUT	
P3.3	39	-	-	-	STD_INOUT	
P3.4	40	-	-	-	STD_INOUT	
P4.0	59	-	-	-	STD_INOUT	
P4.1	60	-	-	-	STD_INOUT	
P4.2	61	-	-	-	STD_INOUT	
P4.3	62	-	-	-	STD_INOUT	
P4.4	63	47	-	-	STD_INOUT	
P4.5	64	48	-	-	STD_INOUT	
P4.6	3	1	-	-	STD_INOUT	
P4.7	4	2	-	-	STD_INOUT	
P4.8	5	-	-	-	STD_INOUT	
P4.9	6	-	-	-	STD_INOUT	
P4.10	7	-	-	-	STD_INOUT	
P4.11	8	-	-	-	STD_INOUT	
VSS	23	17	13	9	Power	Supply GND, ADC reference GND

Table 9 Port I/O Functions (cont'd)

Function	Outputs									Inputs									
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	ALT8	ALT9	Input	Input	Input	Input	Input	Input	Input	Input	Input	
P4.10		LEDTS2. .LINE6	LEDTS2. .COL1	LEDTS1. .COL1	CCU80. OUT00	CCU40. OUT2	USIC1. CH0.SE LO3	CCU81. OUT32	CCU81. OUT00	BCCU0. TRAPIN D	CCU40.I N2AV	CCU41.I N2BA		CCU81.I N3AB		USIC1. CH0.D X2D	USIC1. CH1.DX 5A		
P4.11		LEDTS2. .LINE7	LEDTS2. .COL0	LEDTS1. .COL0	CCU80. OUT01	CCU40. OUT3	USIC1. CH0.SE LO4	CCU81. OUT33	CCU81. OUT01		CCU40.I N3AV	CCU41.I N3BA				USIC1. CH0.D X2E	USIC1. CH1.DX 3A	USIC1. CH1.DX 4A	

Table 10 **Hardware I/O Controlled Functions**

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 11 Absolute Maximum Rating Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition	
		Min	Typ.	Max.			
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_{ST}	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on digital pins with respect to $V_{SSP}^1)$	V_{IN}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Voltage on P2 pins with respect to $V_{SSP}^2)$	V_{INP2}	SR	-0.3	–	$V_{DDP} + 0.3$	V	–
Voltage on analog input pins with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute maximum sum of all input currents during overload condition	ΣI_{IN}	SR	-50	–	+50	mA	–

1) Excluding port pins P2.[1,2,6,7,8,9,11].

2) Applicable to port pins P2.[1,2,6,7,8,9,11].

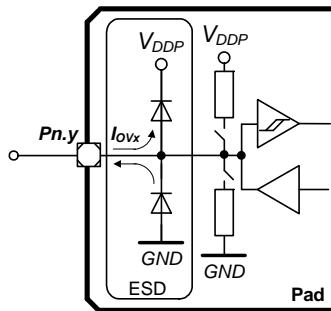

Figure 11 Input Overload Current via ESD structures

Table 13 and **Table 14** list input voltages that can be reached under overload conditions. Note that the absolute maximum input voltages as defined in the **Absolute Maximum Ratings** must not be exceeded during overload.

Table 13 PN-Junction Characterisitics for positive Overload

Pad Type	$I_{ov} = 5 \text{ mA}$
Standard, High-current, AN/DIG_IN	$V_{IN} = V_{DDP} + 0.5 \text{ V}$ $V_{AIN} = V_{DDP} + 0.5 \text{ V}$ $V_{AREF} = V_{DDP} + 0.5 \text{ V}$
P2.[1,2,6:9,11]	$V_{INP2} = V_{DDP} + 0.3 \text{ V}$

Table 14 PN-Junction Characterisitics for negative Overload

Pad Type	$I_{ov} = 5 \text{ mA}$
Standard, High-current, AN/DIG_IN	$V_{IN} = V_{SS} - 0.5 \text{ V}$ $V_{AIN} = V_{SS} - 0.5 \text{ V}$ $V_{AREF} = V_{SS} - 0.5 \text{ V}$
P2.[1,2,6:9,11]	$V_{INP2} = V_{SS} - 0.3 \text{ V}$

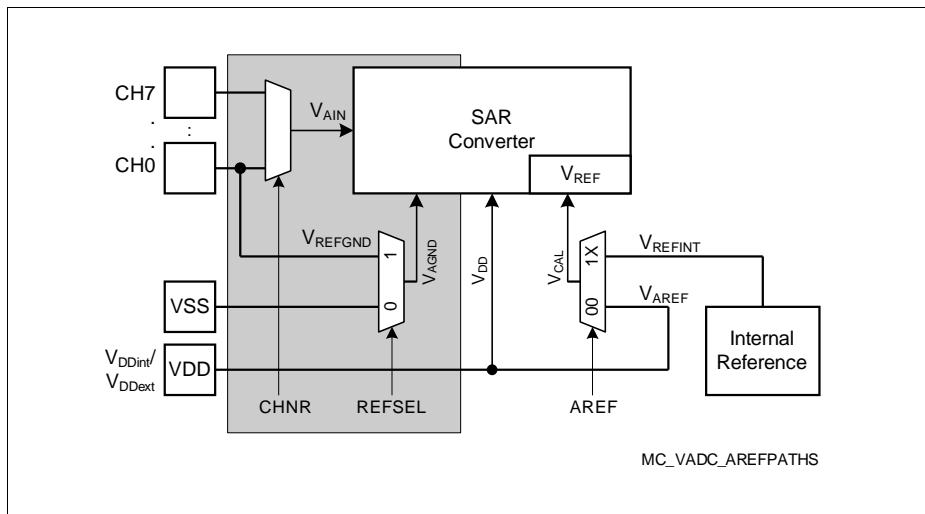


Figure 12 ADC Voltage Supply

3.2.3 Out of Range Comparator (ORC) Characteristics

The Out-of-Range Comparator (ORC) triggers on analog input voltages (V_{AIN}) above V_{DDP} on selected input pins (ORCx.AIN) and generates a service request trigger (ORCx.OUT).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 18 Out of Range Comparator (ORC) Characteristics (Operating Conditions apply; $V_{DDP} = 3.0 \text{ V} - 5.5 \text{ V}$; $C_L = 0.25\text{pF}$)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
DC Switching Level	V_{ODC}	CC	—	—	180	mV $V_{AIN} \geq V_{DDP} + V_{ODC}$
Hysteresis	V_{OHYS}	CC	15	—	54	mV
Always detected Overvoltage Pulse	t_{OPDD}	CC	103	—	—	ns $V_{AIN} \geq V_{DDP} + 150 \text{ mV}$
			88	—	—	ns $V_{AIN} \geq V_{DDP} + 350 \text{ mV}$
Never detected Overvoltage Pulse	t_{OPDN}	CC	—	—	21	ns $V_{AIN} \geq V_{DDP} + 150 \text{ mV}$
			—	—	11	ns $V_{AIN} \geq V_{DDP} + 350 \text{ mV}$
Detection Delay	t_{ODD}	CC	39	—	132	ns $V_{AIN} \geq V_{DDP} + 150 \text{ mV}$
			31	—	121	ns $V_{AIN} \geq V_{DDP} + 350 \text{ mV}$
Release Delay	t_{ORD}	CC	44	—	240	ns $V_{AIN} \leq V_{DDP}; V_{DDP} = 5 \text{ V}$
			57	—	340	ns $V_{AIN} \leq V_{DDP}; V_{DDP} = 3.3 \text{ V}$
Enable Delay	t_{OED}	CC	—	—	300	ns $\text{ORCCTRL.ENORCx} = 1$

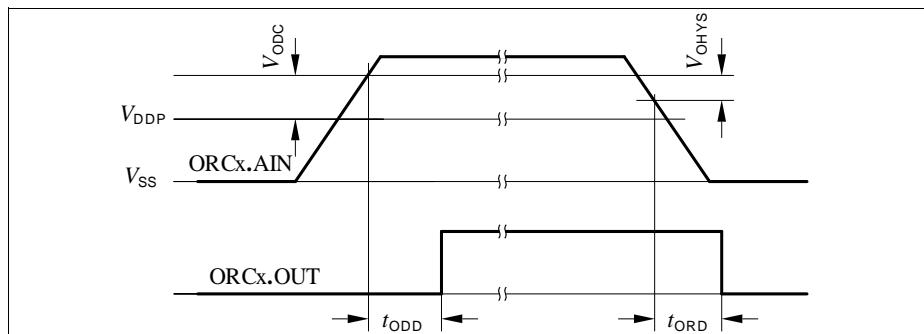


Figure 13 ORCx.OUT Trigger Generation

3.2.5 Temperature Sensor Characteristics

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 20 Temperature Sensor Characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Measurement time	t_M CC	–	–	10	ms	
Temperature sensor range	T_{SR} SR	-40	–	115	°C	
Sensor Accuracy ¹⁾	T_{TSAL} CC	-6	–	6	°C	$T_J > 20^\circ\text{C}$
		-10	–	10	°C	$0^\circ\text{C} \leq T_J \leq 20^\circ\text{C}$
		–	-/+8	–	°C	$T_J < 0^\circ\text{C}$
		–	–	15	μs	
Start-up time	t_{TSST} SR	–	–	15	μs	

1) The temperature sensor accuracy is independent of the supply voltage.

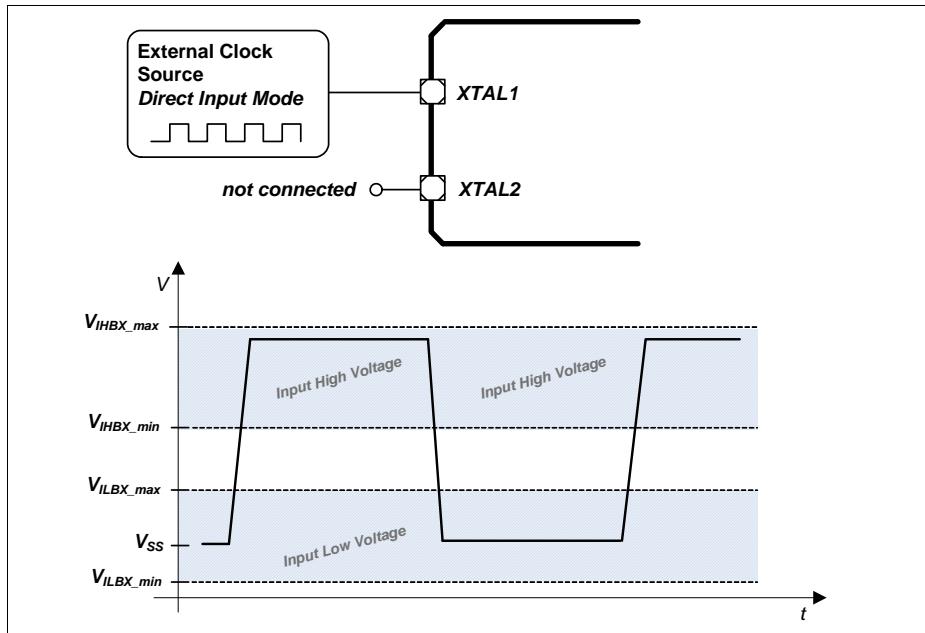


Figure 16 Oscillator in Direct Input Mode

3.2.8 Flash Memory Parameters

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 25 Flash Memory Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Erase time per page / sector	t_{ERASE} CC	6.8	7.1	7.6	ms	
Program time per block	t_{PSER} CC	102	152	204	μs	
Wake-Up time	t_{WU} CC	–	32.2	–	μs	
Read time per word	t_a CC	–	50	–	ns	
Data Retention Time	t_{RET} CC	10	–	–	years	Max. 100 erase / program cycles
Flash Wait States ¹⁾	N_{WSFLASH} CC	0	0	0		$f_{\text{MCLK}} = 8 \text{ MHz}$
		0	1	1		$f_{\text{MCLK}} = 16 \text{ MHz}$
		1	2	2		$f_{\text{MCLK}} = 32 \text{ MHz}$
		2	2	3		$f_{\text{MCLK}} = 48 \text{ MHz}$
Erase Cycles	N_{ECYC} CC	–	–	$5 \cdot 10^4$	cycles	Sum of page and sector erase cycles
Total Erase Cycles	N_{TECYC} CC	–	–	$2 \cdot 10^6$	cycles	

1) Flash wait states are automatically inserted by the Flash module during memory read when needed. Typical values are calculated from the execution of the Dhrystone benchmark program.

Electrical Parameter

Table 26 Power-Up and Supply Threshold Parameters (Operating Conditions apply) (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
V_{DDP} brownout reset voltage	V_{DDPBO} CC	1.55	1.62	1.75	V	calibrated, before user code starts running
V_{DDP} voltage to ensure defined pad states	V_{DDPPA} CC	–	1.0	–	V	
Start-up time from power-on reset	t_{SSW} SR	–	260	–	μs	Time to the first user code instruction ³⁾
BMI program time	t_{BMI} SR	–	8.25	–	ms	Time taken from a user-triggered system reset after BMI installation is requested

1) A capacitor of at least 100 nF has to be added between V_{DDP} and V_{SSP} to fulfill the requirement as stated for this parameter.

2) Valid for a 100 nF buffer capacitor connected to supply pin where current from capacitor is forwarded only to the chip. A larger capacitor value has to be chosen if the power source sink a current.

3) This values does not include the ramp-up time. During startup firmware execution, MCLK is running at 48 MHz and the clocks to peripheral as specified in register CGATSTAT0 are gated.

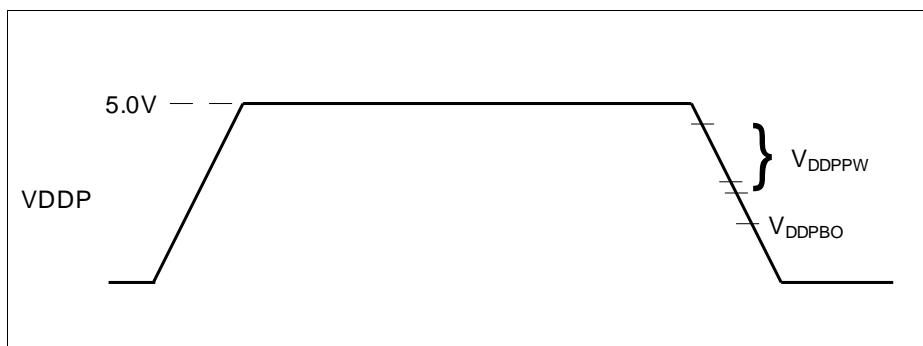
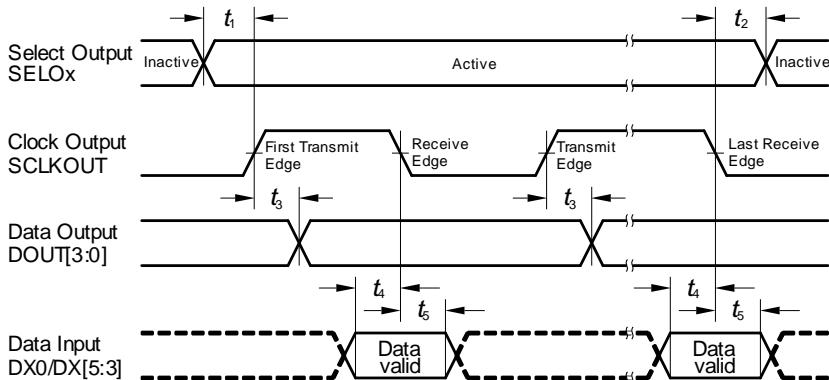
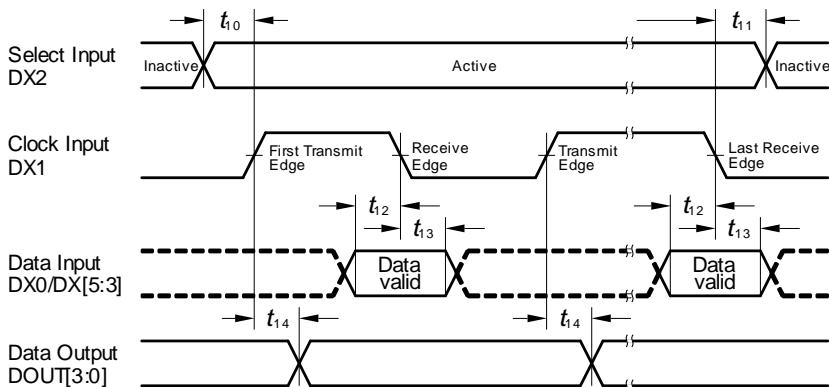


Figure 23 Supply Threshold Parameters

Electrical Parameter
Table 32 USIC SSC Slave Mode Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 hold after last clock input DX1 receive edge ¹⁾	t_{11} SR	17	—	—	ns	
Receive data input DX0/DX[5:3] setup time to shift clock receive edge ¹⁾	t_{12} SR	21	—	—	ns	
Data input DX0/DX[5:3] hold time from clock input DX1 receive edge ¹⁾	t_{13} SR	15	—	—	ns	
Data output DOUT[3:0] valid time	t_{14} CC	-	—	71	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

Master Mode Timing

Slave Mode Timing


Transmit Edge: with this clock edge transmit data is shifted to transmit data output

Receive Edge: with this clock edge receive data at receive data input is latched

Drawn for BRGH.SCLKCFG = 00_B. Also valid for SCLKCFG = 01_B with inverted SCLKOUT signal

USIC_SSC_TMGX.VSD

Figure 25 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration, for which the slave select signal is low-active, and the serial clock signal is not shifted and not inverted.

3.3.6.2 Inter-IC (IIC) Interface Timing

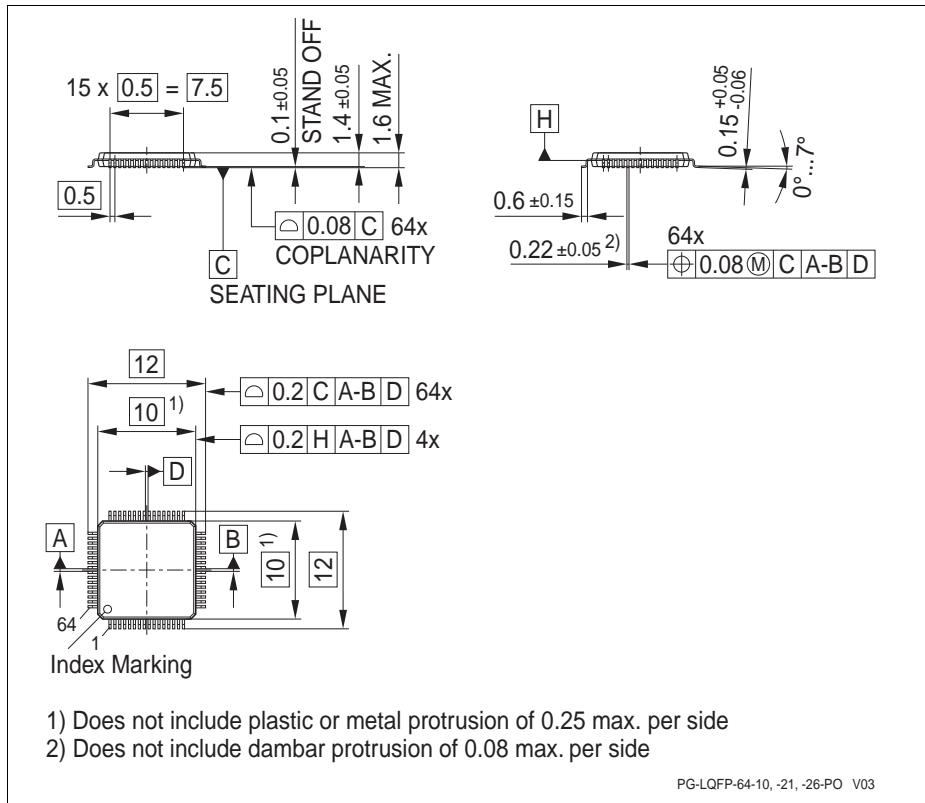
The following parameters are applicable for a USIC channel operated in IIC mode.

Note: Operating Conditions apply.

Table 33 USIC IIC Standard Mode Timing¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	-	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	-	-	1000	ns	
Data hold time	t_3 CC/SR	0	-	-	μs	
Data set-up time	t_4 CC/SR	250	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	4.7	-	-	μs	
HIGH period of SCL clock	t_6 CC/SR	4.0	-	-	μs	
Hold time for (repeated) START condition	t_7 CC/SR	4.0	-	-	μs	
Set-up time for repeated START condition	t_8 CC/SR	4.7	-	-	μs	
Set-up time for STOP condition	t_9 CC/SR	4.0	-	-	μs	
Bus free time between a STOP and START condition	t_{10} CC/SR	4.7	-	-	μs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.


Figure 32 PG-LQFP-64-26